

Device Modeling Report

COMPONENTS: THYRISTOR
PART NUMBER: BT152B-400R
MANUFACTURER: PHILIPS SEMICONDUCTOR



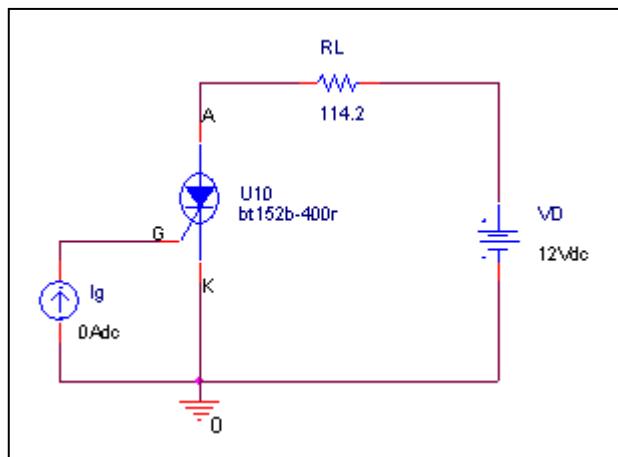
Bee Technologies Inc.

DIODE MODEL

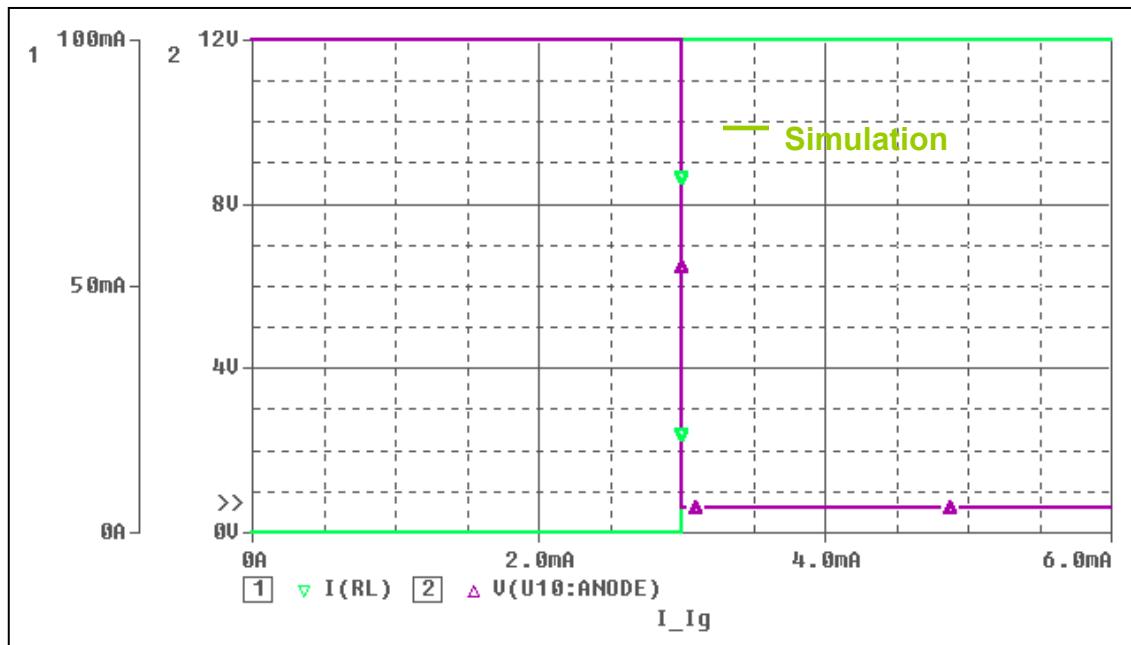
Pspice model Parameter	Model description
IS	Saturation Current
N	Emission Coefficient
RS	Series Resistance
IKF	High-injection Knee Current
CJO	Zero-bias Junction Capacitance
M	Junction Grading Coefficient
VJ	Junction Potential
ISR	Recombination Current Saturation Value
BV	Reverse Breakdown Voltage(a positive value)
IBV	Reverse Breakdown Current(a positive value)
TT	Transit Time

IG-VT Characteristic

Evaluation Circuit



Simulation result

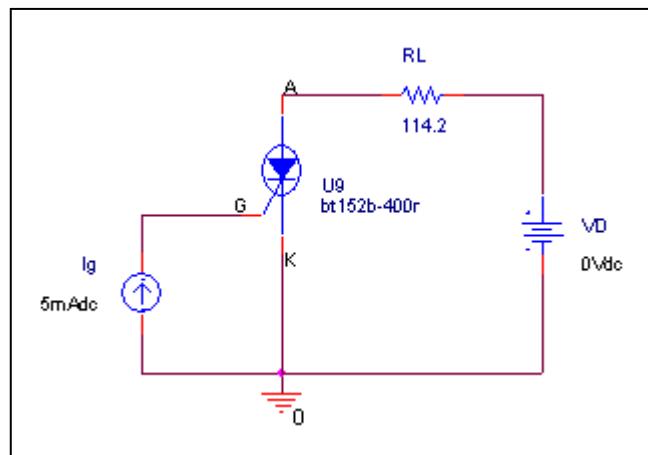


Comparison Table

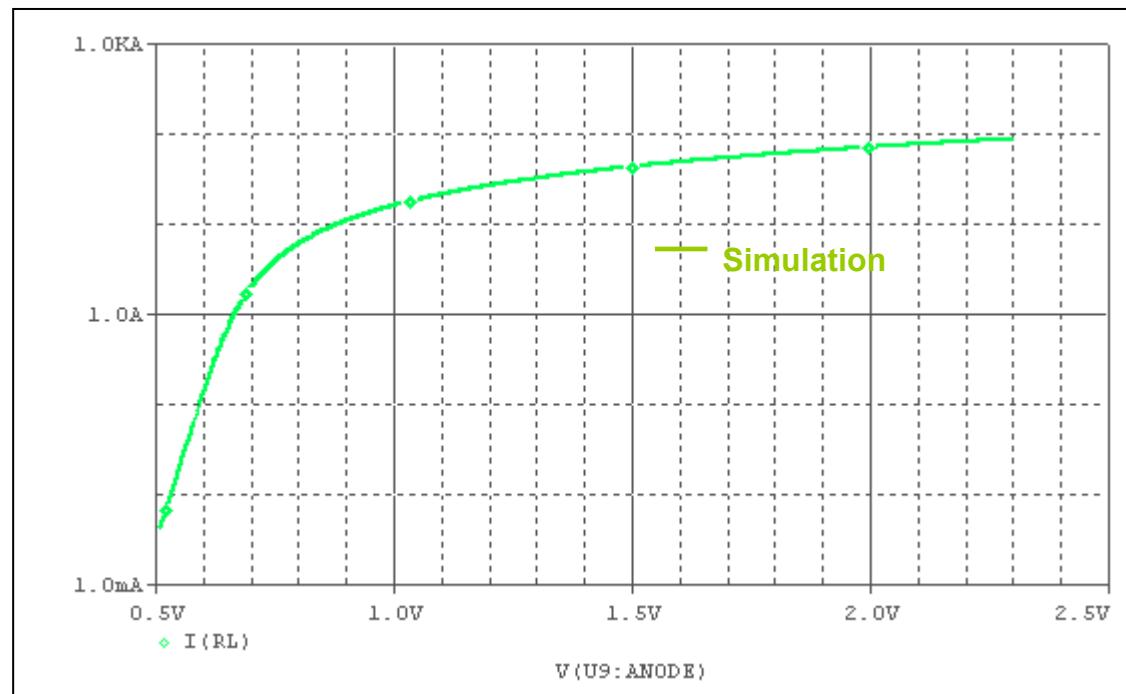
	Measurement	Simulation	% Error
I _{G_T} (mA)	3	2.9923	-0.25667
V _{G_T} (V)	0.6	0.591412	-1.43133

ITM-VTM Characteristic

Evaluation Circuit



Simulation result

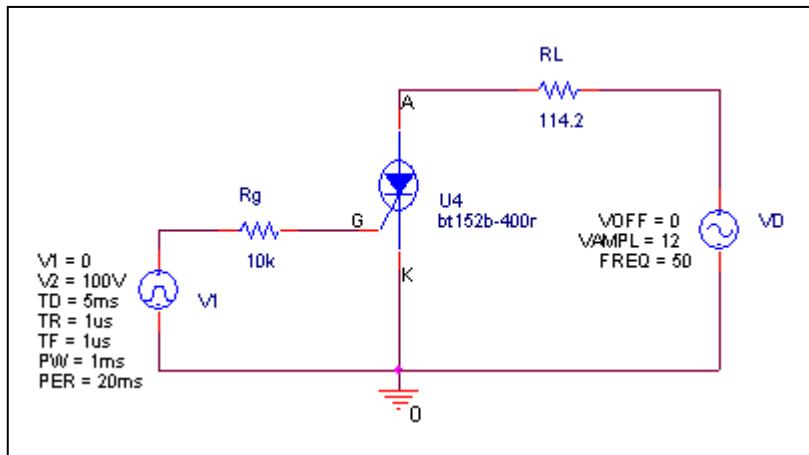


Comparison Table

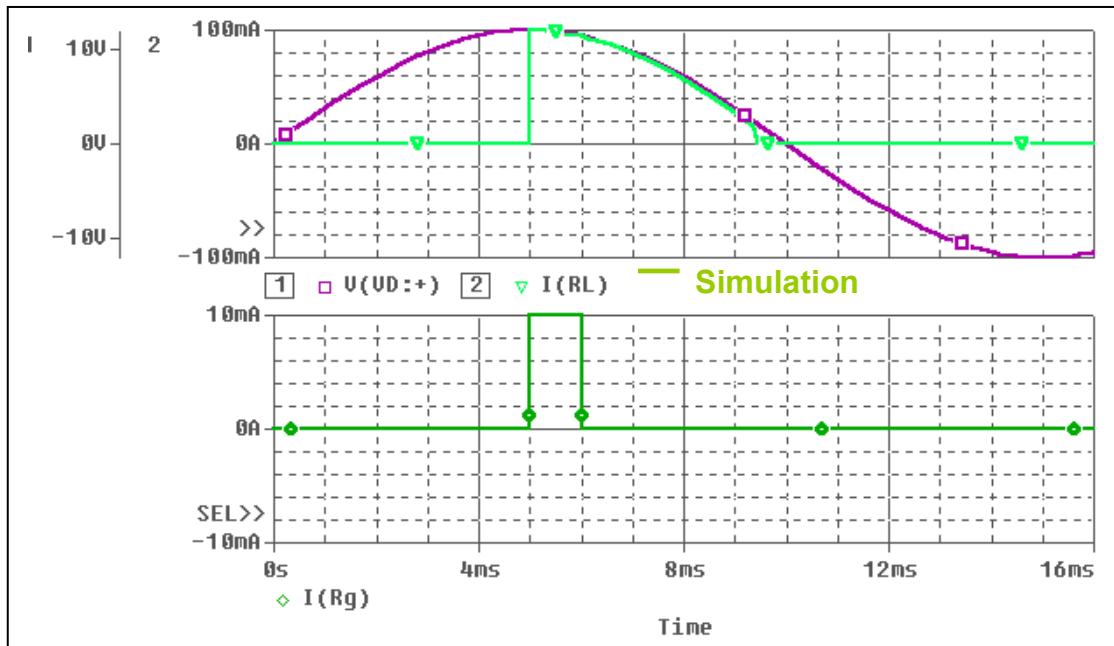
At ITM=40A	Measurement	Simulation	% Error
VTM(V)	1.4	1.4527	3.76429

Holding Characteristic (IH)

Evaluation Circuit



Simulation result

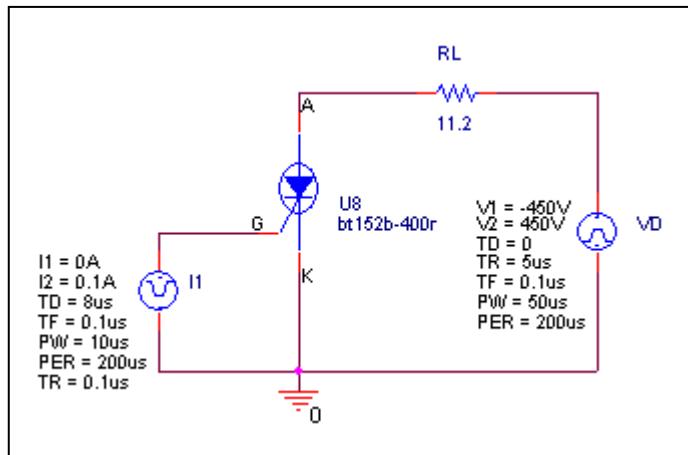


Comparison Table

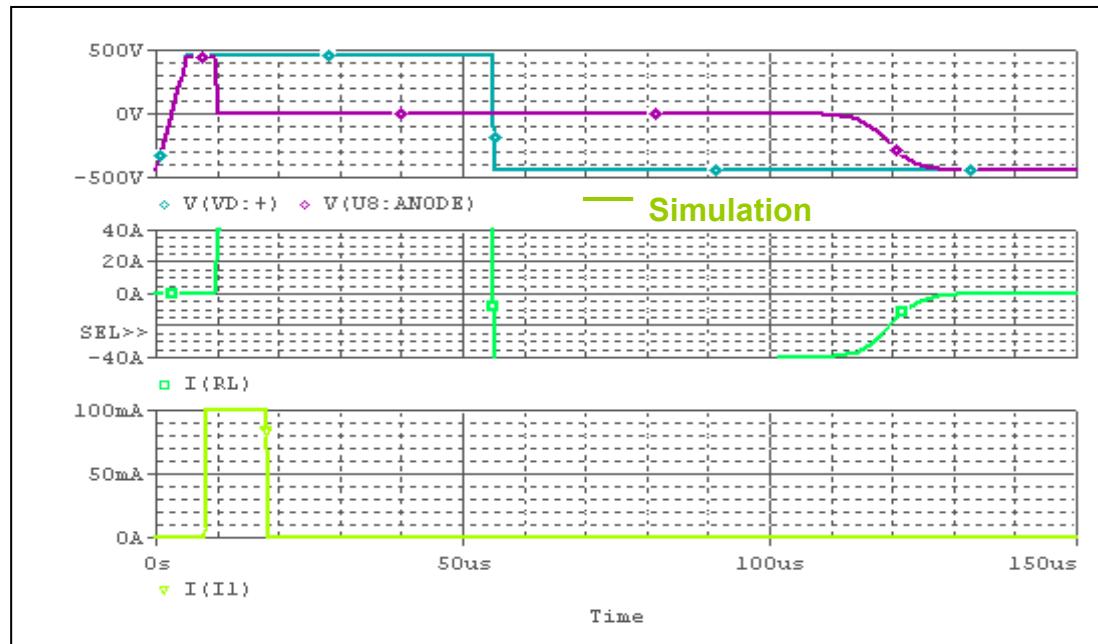
$VD=12V$	Measurement	Simulation	% Error
$I_H(mA)$	15	15.100	0.66667

Switching Time Characteristic

Evaluation Circuit



Simulation result



Comparison Table

	Measurement	Simulation	%Error
Ton(us)	2	2.0532	2.66000
Toff(us)	70	69.671	-0.47000